



SIM900 V2.03

Reliability Test Report

Report by: Sun ping

Confirmed by: Shen Feng

Approved by: Yongsheng.li

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1. Purpose

The document provides detailed reliability test conditions and data for SIM900 under different temperature, humidity and vibration.

2. Reference Standards

IEC 60068-2

ETSI GSM 3GPP phase2+

SIMCOM Reliability Handbook

YD/T1215

3. Test Equipment

R&S CMU200 Universal Radio Communication Tester

KSON Temperature Chamber

KSON Temperature and Humidity Lab Tester

STI D-150-2

4. Functional Check

Functional check before reliability test and recheck after this test is obligatory in order to ensure that the changes caused by the test are under accepted tolerance.

4.1 Call Set Up

The module can register on an actual network and establish a call normally with a User SIM card.

4.2 Serial Port Communication Test

The module can communicate with a PC via AT commands through a serial port correctly.

4.3 GSM RF Test

On the basis of the performance requirements and the GSM Specification, measurements are to be carried out. These input measurements will be used to determine whether there have been any electromagnetic or radio-engineering changes after environmental tests.

Measuring parameters:

- Conducted transmitter output power
- Transmitter output power versus time
- Peak phase errors (peak), RMS phase errors and frequency errors
- Output RF spectrum due to modulation and switching
- Receiver Bit Error Ratio (BER) performance

The above parameters are measured in low, middle, high channels and at low, middle, high power levels.

All measured results should meet the requirements of 3GPP TS51.010 Specification.

4.4 Call Success Rate Test

- Establish a call with CMU200 via AT commands successfully and then disconnect.
- Repeat the above step for 2000 times.
- Calculate call success rate with the formula below:

$$\text{Call success rate} = (\text{Call Success times} / \text{all dialed times}) * 100\%$$

5. Environmental and Reliability Test Result

No.	Test Item	Test Condition	Qty.	Test Result	Standards
1	Cold Test	-30℃ 16h (operation)	4	Pass	GB/T 2423.1-2001 Test Ab IEC 68-2-1 Test
		-40℃ 16h (Restricted operation)	4	Pass	
2	Dry Heat	+80℃ 16h (operation)	4	Pass	GB/T 2423.1-2001 Test Ab IEC 68-2-1 Test
		+85℃ 16h (Restricted operation)	4	Pass	
3	Cold Storage	-45℃ 72h	10	Pass	GB/T 2423.1-2001 Test A
4	Dry Storage	+90℃ 72h	10	Pass	GB/T 2423.2-2001 Test Bb
5	Temperature change(shock)	Low Temp: -40℃ 30min High Temp: +85℃ 30min Cycles: 144	10	Pass	GB/T 2423.22-2002 Test Na IEC 68-2-14 Na
6	Damp Heat Cyclic	High Temperature: +55℃ Humidity: 93%-100% Cycles: 6	10	Pass	IEC 68-2-30 Db Test
7	Random Vibration	5-20Hz:0.96m2/s3 20-500Hz:-3dB/oct 3 axes , 30min per axis	3	Pass	GB/T 2423.13-1997 Test Fdb IEC 68-2-36 Fdb Test
8	Shock Test	100g 6ms 3*6=18shocks	3	Pass	ISO 16750-3 IEC 68-2-27
9	Bump Test	25g 6ms 6*1000=6000	3	Pass	ISO 16750-3 IEC 68-2-29
10	Micro-drop Test	10cm , 10000 times	2	Pass	SIM Internal Standard
11	MTBF	High Temperature :80℃ MTBF≥133690hours	10	Pass	SIM Internal Standard

6. Test Items and Conditions

6.1. Cold Test (Operation)

Temperature: -30°C

Test duration: 16h

Test Unit Status: Power On

Procedure:

Put the modules into the temperature chamber, the modules have to be incubated for at least 12 h for temperature adjustment before measuring, and then carry out measurement of modules to be tested in the chamber.

a) Serial port communication test

b) GSM RF test (please refer to [Chapter 7 table 1-3](#))

c) Call success rate test

Result: Pass

6.2. Cold Test (Restricted operation)

Temperature: -40°C

Test duration: 16h

Test Unit Status: Power On

Procedure:

Put the modules into the temperature chamber, the modules have to be incubated for at least 12 h for temperature adjustment before measuring, and then carry out measurement of modules to be tested in the chamber.

a) RF-Test at high, Normal and Low Voltage. Set up a call connect with CMU200, during the test, RF characteristics have to be observed. Record the abnormal parameters for RD department to reference

b) Serial Port Communication test

c) *Call success rate Test*

Result: Pass

6.3. Dry Heat Test (Operation)

Temperature: +80 °C

Test duration: 16h

Test Unit Status: Power On

Procedure:

Put the modules into the temperature chamber, the modules have to be incubated for at least 12 h for temperature adjustment before measuring, and then carry out measurement of modules to be tested in the chamber.

- a) *GSM RF-Test at high, Normal and Low Voltage. (please refer to [Chapter 7 table 1-3](#))*
- b) *Serial Port Communication test*
- c) *Call success rate Test*

Result: Pass

6.4. Dry Heat Test (Restricted Operation)

Temperature: +85 °C

Test duration: 16h

Test Unit Status: Power On

Procedure:

Put the modules into the temperature chamber, the modules have to be incubated for at least 12 h for temperature adjustment before measuring, and then carry out measurement of modules to be tested in the chamber.

- a) *RF-Test at high, Normal and Low Voltage. Set up a call connect with CMU200, during the test, RF characteristics have to be observed. Record the abnormal parameters for RD department to reference*

b) *Serial Port Communication test*

c) *Call success rate Test*

Result: Pass

6.5. Cold Storage Test

Temperature: *-45 °C*

Test duration: *72h*

Test Unit Status: *Power Off*

Procedure:

After 72h low-temperature storage, remove the modules from the temperature chamber to room temperature environment at least 120 min.

Test the actual network calls, serial port communication.

Result: Pass

6.6. Dry Heat Storage Test

Temperature: *+85 °C*

Test duration: *72h*

Test Unit Status: *Power Off*

Procedure:

After 72h high-temperature storage, remove the modules from the temperature chamber and place it at room temperature environment at least 120 min.

Test the actual network calls, serial port communication.

Result: Pass

6.7. Temperature Change (Shock)

Low Temperature: *-40 °C*

High Temperature: *+85 °C*

Change Over time: <30 seconds (dual chamber system)

< 1 min (triple chamber system)

Test duration: 1h

Number of repetitions: 144

Test Unit Status: Power Off

Procedure:

After thermal shock, remove the modules from the temperature chamber to room temperature environment at least 120 min.

Test the actual network calls, serial port communication.

Result: Pass

6.8. Damp Heat Cyclic Test

Low Temperature: +25 °C ±2 °C

High Temperature: +55 °C ±2 °C

Humidity: 93% ±3%

Number of repetitions: 6

Test duration: 12h+12h

Test Unit Status: Power On

Procedure:

After damp heat, remove the module from the temperature and Humidity chamber to room temperature environment at least 120 min.

Test the actual network calls, serial port communication functions.

Result: Pass

6.9. Random Vibration

Frequency range: 10-1000 Hz

Acceleration: $G_{RMS} = 27.8 \text{ m/s}^2$

Frequency Hz	PSD (m/s ²) ² /Hz
10	20
55	6.5
180	0.25
300	0.25
360	0.14
1000	0.14

Duration: 3 x 8h

Test: all 3 axes (X, Y, Z)

Test Unit Status: Power On

Procedure:

- 1) Fix the module to the vibration table.
- 2) Establish a call connection with CMU200 or 8960, during the vibration, RF characteristics have to be observed. All RF parameters limits can not be exceeded
- 3) After random vibration, test RF characteristics at normal voltage.,(Please refer to [Chapter 7 table 4](#))
- 4) Test serial port communication function.

Remark: Modules must be fixed on the fixture tool and then not allow to be moved. The material of the fixture tool should be aluminum.

Result: Pass

6.10. Mechanical Shock Test

Acceleration: 100g

Duration: 6ms

Pulse Shape: Half-Sine Waveform

Test: 3shocks for each of six axes (+/-X, +/-Y, +/-Z)

Total: 18shocks

Procedure:

Fix the module to the shock table, then shock.

Result: Pass

6.11. Bump Test

Acceleration: 25g

Duration: 6ms

Pulse Shape: Half-Sine Waveform

Test: 1000 shocks for each of six axes (+/-X, +/-Y, +/-Z)

Total: 6000shocks

Procedure:

Fix the module to the shock table, then bump

Result: Pass

6.12. Micro-drop Test

Height: 10cm

Surface (floor): concrete or steel

Number of drops: 10000 (front and back surface, each surface for 5000)

Measuring Intervals: 1000

Procedure:

The module will be dropped from 10cm height to the concrete or steel surface floor, repeat the above step 5000 times for each surface.

Test the actual network calls, serial port communication

Result: Pass

6.13. Estimation of MTBF

1) Reliability data (acceleration life tests data)

Operating Life: $T_a = 80(\text{degree C})$

Test duration time: $t = 10 * 24h = 240h$

Total sample quantity of series = 10 pieces

Failure = 0 pieces

Sample information:

- 1) Hardware Revision: SIM900 V2.03
- 2) Software Revision: 1137B05V03SIM900M64_ST

2) Calculation of the acceleration characteristics

First of all, the following equation is assumed as model of accelerated life test.

$$AF := \exp \left[\frac{E_A}{K} \left(\frac{1}{T_o} - \frac{1}{T_a} \right) \right]$$

AF: Temperature acceleration factor

Ea: Activation Energy by Temperature (0.8eV)

K: Boltzmann's Constant (8.6157x10-5)

To: Actual use average Temperature (To = 25+273=298°K)

Ta: Test Temperature (Ta =80+273=353°K)

Calculation of Temperature acceleration factor:

$$AF = \exp [Ea/K*(1/298-1/ (273+80))] \\ = \exp (0.8/ (8.617*10^{-5})*(1/298-1/353)) = 128.26$$

So, total device hour at 25(degree C) is calculated as follows:

$$\text{Total device hour } T = (10 \text{ pieces} \times 240\text{hours}) \times 128.26 = 307824 \text{ hours}$$

3) The One-sided 90% confidential intervals for MTBF (θ)

According to MIL-HDBK -338B 8.3.2.5.2 Confidence Limits - Exponential Distribution,

Calculation MTBF:

$$\theta = \left(\frac{2T}{\chi^2(\alpha, 2r + 2)}, \infty \right) \\ = (2*307824/\chi^2(0.1,2), \infty) = (2*307824/4.605, \infty) = (133690, \infty)$$

MTBF ≥ 133690 hours

(The following Appendix 7.5 is the $X^2(p, d)$ data, $X^2(0.1, 2) = 4.605$)

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7. Appendix

7.1 Table1 GSM RF Test data

GSM RF Test Report								
GSM900		Frequency Error	Phase Error		Power	P/T	Modulation	Switching
			Peak	RMS				
		<0.1ppm	<20 °	<5 °				
RTNV*	1	-46.4	5.4	1.5	32.4	PASS	PASS	PASS
	62	-32	4.9	1.5	32.4	Pass	PASS	PASS
	124	-35.4	5.2	1.3	32.4	Pass	PASS	PASS
LTHV*	1	-24.6	3.1	0.9	33.4	PASS	PASS	PASS
	62	9.5	4.2	1	33.3	Pass	PASS	PASS
	124	23.1	4.9	1.1	33	Pass	PASS	PASS
LTLV*	1	11.3	2.8	0.9	33.2	PASS	PASS	PASS
	62	-5.2	2.8	1	32.7	Pass	PASS	PASS
	124	24.2	3.5	0.9	32.4	Pass	PASS	PASS
HTLV*	1	-16.1	3.4	1.3	32	PASS	PASS	PASS
	62	-30.5	4.9	1.5	31.5	Pass	PASS	PASS
	124	-21.5	4.6	1.3	31.1	Pass	PASS	PASS
HTHV*	1	-49	5.1	1.4	32.3	PASS	PASS	PASS
	62	-33.8	4.6	1.3	32.1	Pass	PASS	PASS
	124	-30	4.3	1.3	31.9	Pass	PASS	PASS
DCS1800		Frequency Error	Phase Error		Power	P/T	Modulation	Switching
		<0.1ppm	<20 °	<5 °				
RTNV*	512	-88.1	7.3	1.8	29.5	PASS	PASS	PASS
	698	-67.7	6.8	1.7	29.5	Pass	PASS	PASS
	885	-72.9	7	1.9	29.5	Pass	PASS	PASS
LTHV*	512	10.7	5.8	2	30.5	PASS	PASS	PASS
	698	-18.5	5.1	1.8	29.6	Pass	PASS	PASS
	885	18.1	5.8	2	29.5	Pass	PASS	PASS
LTLV*	512	-55.8	5.8	2	30.1	PASS	PASS	PASS
	698	-18	4.8	1.8	30.1	Pass	PASS	PASS
	885	24.1	6.4	2.2	30	Pass	PASS	PASS
HTLV*	512	-75.4	5.7	1.7	29.5	PASS	PASS	PASS
	698	-56.1	5.7	1.7	29.2	Pass	PASS	PASS
	885	-63.9	6	1.7	29.1	Pass	PASS	PASS
HTHV*	512	-57.7	5.9	1.6	29.0	PASS	PASS	PASS
	698	-68.2	6.6	1.7	28.6	Pass	PASS	PASS

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	885	-72.9	4.9	1.8	28.6	Pass	PASS	PASS
GSM850	PCL	Frequency Error	Phase Error		Power	P/T	Modulation	Switching
			Peak	RMS				
		<0.1ppm	<20°	<5°				
RTNV*	128	-40.6	6.6	1.6	32.8	PASS	PASS	PASS
	189	-32.8	4.6	1.5	32.8	Pass	PASS	PASS
	251	-32.4	4.6	1.4	32.7	Pass	PASS	PASS
LTHV*	128	24.3	2.7	1	32.9	PASS	PASS	PASS
	189	18.5	2.7	1	33.1	Pass	PASS	PASS
	251	19.6	2.9	1.1	32.9	Pass	PASS	PASS
LTLV*	128	19.1	2.8	1	32.8	PASS	PASS	PASS
	189	20.4	3.3	1	32.6	Pass	PASS	PASS
	251	13.7	2.6	0.9	32.5	Pass	PASS	PASS
HTLV*	128	-75.4	5.7	1.7	29	PASS	PASS	PASS
	189	-56.1	5.7	1.7	29.2	Pass	PASS	PASS
	251	-63.9	6	1.7	29.1	Pass	PASS	PASS
HTHV*	128	-70.1	5.7	1.6	29.5	PASS	PASS	PASS
	189	-63.7	5.5	1.8	29.2	Pass	PASS	PASS
	251	-67.2	5.7	1.9	29.1	Pass	PASS	PASS
PCS1900	PCL	Frequency Error	Phase Error		Power	P/T	Modulation	Switching
			Peak	RMS				
		<0.1ppm	<20°	<5°				
RTNV*	512	-88.1	7.3	1.8	29.5	PASS	PASS	PASS
	661	-67.7	6.8	1.7	29.5	Pass	PASS	PASS
	810	-72.9	7	1.9	29.5	Pass	PASS	PASS
LTHV*	512	-75.4	5.7	1.7	29.7	PASS	PASS	PASS
	661	-56.1	5.7	1.7	29.8	Pass	PASS	PASS
	810	-63.9	6	1.7	29.4	Pass	PASS	PASS
LTLV*	512	28.7	5.4	2	29.3	PASS	PASS	PASS
	661	-11.2	8.1	2.2	29.2	Pass	PASS	PASS
	810	-25.4	5	1.8	29.2	Pass	PASS	PASS
HTLV*	512	-23.1	5.3	2.1	29.8	PASS	PASS	PASS
	661	22.4	5.2	2	29.7	Pass	PASS	PASS
	810	-24.1	5	1.8	29.7	Pass	PASS	PASS
HTHV*	512	-41.5	7.8	2	28.9	PASS	PASS	PASS
	661	-66.6	5.2	2	28.4	Pass	PASS	PASS
	810	-83.2	6.3	2	28.3	Pass	PASS	PASS

Remark: * RTNV: Room Temp 25°C Normal Voltage 3.8V

* LTHV: Low Temp -30°C High Voltage 4.75V

* LTLV: Low Temp -30°C Low Voltage 3.15V

* HTHV: High Temp 80°C High Voltage 4.75V

* HTLV: High Temp 80°C Low Voltage 3.15V

7.2 Table 2: GPRS Transmitter Characteristics Test Data

GPRS RF Test Report								
GSM900		Frequency Error	Phase Error		Power	P/T	Modulation	Switching
			Peak	RMS				
		<0.1ppm	<±20	<5				
LTHV*	1	-41.94	6.3	2.4	32.8	PASS	PASS	PASS
	62	-36.6	6.5	2.2	32.9	Pass	PASS	PASS
	124	-13.97	-6.3	2.2	32.7	Pass	PASS	PASS
HTLV*	1	-41.94	-6.2	2.3	32.1	PASS	PASS	PASS
	62	-36.6	6.1	2.3	31.8	Pass	PASS	PASS
	124	-13.97	6.3	2.3	31.6	Pass	PASS	PASS
DCS1800		Frequency Error	Phase Error		Power	P/T	Modulation	Switching
			Peak	Peak				
		<0.1ppm	<20°	<5°				
LTHV*	512	-26.58	-6.7	2.3	29.1	PASS	PASS	PASS
	698	-35.55	-6.7	2.2	29.5	Pass	PASS	PASS
	885	-68.68	6.8	2.2	29.4	Pass	PASS	PASS
HTLV*	512	-75.57	-6.4	2.4	28.8	PASS	PASS	PASS
	698	-69.94	-7.3	2.3	28.7	Pass	PASS	PASS
	885	-54.7	7.1	2.2	28.9	Pass	PASS	PASS
GSM850	PCL	Frequency Error	Phase Error		Power Peak	P/T	Modulation	Switching
			Peak	Peak				
		<0.1ppm	<20°	<5°				
LTHV*	128	-12.97	6.1	2.2	32.5	PASS	PASS	PASS
	189	-45.95	6.7	2.2	32.6	Pass	PASS	PASS
	251	-42.76	6.4	2.1	32.5	Pass	PASS	PASS
HTLV*	128	6.06	7.0	2.1	32.0	PASS	PASS	PASS
	189	-30.61	-6.0	2.3	31.8	Pass	PASS	PASS
	251	-43.96	6.1	2.1	31.9	Pass	PASS	PASS
PCS1900	PCL	Frequency Error	Phase Error		Power Peak	P/T	Modulation	Switching
			Peak	Peak				
		<0.1ppm	<20°	<20°				
LTHV*	512	-69.11	6.4	2.4	29.5	PASS	PASS	PASS

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	661	-86.94	-6.6	2.4	29.4	Pass	PASS	PASS
	810	-51.69	6.8	2.3	29.6	Pass	PASS	PASS
HTLV*	512	-59.84	-6.5	2.3	29.3	PASS	PASS	PASS
	661	-29.45	6.4	2.4	29.0	Pass	PASS	PASS
	810	-69.91	6.8	2.3	28.9	Pass	PASS	PASS

7.3 Table 3 GPRS RF Rx sensitivity Test Record

LTHV*	Class10	4D1Up	3D2Up	2D2Up	1D2Up
GSM900 CH62	CS-2(-103dB)	0	0	0	0
	CS-4(-100dB)	0	0	0	0
	Result	PASS	PASS	PASS	PASS
DCS1800 CH698	CS-2(-101dB)	0	0	0	0
	CS-4(-98dB)	0	0	0	0
	Result	PASS	PASS	PASS	PASS
GSM850 CH189	CS-2(-103dB)	0	0	0	0
	CS-4(-100dB)	0	0	0	0
	Result	PASS	PASS	PASS	PASS
PCS1900 CH661	CS-2(-101dB)	0	0	0	0
	CS-4(-98dB)	0	0	0	0
	Result	PASS	PASS	PASS	PASS
HTLV*	Class10	4D1Up	3D2Up	2D2Up	1D2Up
GSM900 CH62	CS-2(-103dB)	0	0	0	0
	CS-4(-100dB)	0	0	0	0
	Result	PASS	PASS	PASS	PASS
DCS1800 CH698	CS-2(-101dB)	0	0	0	0
	CS-4(-98dB)	0	0	0	0
	Result	PASS	PASS	PASS	PASS
GSM850 CH189	CS-2(-103dB)	0	0	0	0
	CS-4(-100dB)	0	0	0	0
	Result	PASS	PASS	PASS	PASS
PCS1900 CH661	CS-2(-101dB)	0	0	0	0
	CS-4(-98dB)	0	0	0	0
	Result	PASS	PASS	PASS	PASS

7.4 Table 4 RF Test Record of Vibration Test

900MHz	PCL	Frequency Error	Phase Error Peak	Phase Error RMS	Power	P/T	Modulation	Switching
		<0.1ppm	<20 °	<5 °				

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		Frequency Error	Phase Error Peak	Phase Error RMS	Power	P/T	Modulation	Switching
1	5	-46.4	5.4	1.5	32.4	Pass	Pass	Pass
	12	-36.5	3.4	1.3	18.8	Pass	Pass	Pass
	19	-32.4	3.6	1.5	4.9	Pass	Pass	Pass
62	5	-32	4.9	1.5	32.4	Pass	Pass	Pass
	12	-35.6	3.8	1.4	18.7	Pass	Pass	Pass
	19	-35.3	3.6	1.4	4.9	Pass	Pass	Pass
124	5	-35.4	5.2	1.3	32.4	Pass	Pass	Pass
	12	-31.7	3.6	1.4	18.7	Pass	Pass	Pass
	19	-28.5	3.6	1.4	4.8	Pass	Pass	Pass
1800MHz	PCL	Frequency Error	Phase Error Peak	Phase Error RMS	Power	P/T	Modulation	Switching
		<0.1ppm	<20°	<5°				
512	0	-88.1	7.3	1.8	29.5	Pass	Pass	Pass
	7	-82.8	4.7	1.5	16.1	Pass	Pass	Pass
	15	-73.5	5.9	1.7	0.3	Pass	Pass	Pass
698	0	-67.7	6.8	1.7	29.5	Pass	Pass	Pass
	7	-70.9	4.5	1.5	16.2	Pass	Pass	Pass
	15	-65.9	5.4	1.6	0.3	Pass	Pass	Pass
885	0	-72.9	7	1.9	29.5	Pass	Pass	Pass
	7	-89	5.2	1.6	16.1	Pass	Pass	Pass
	15	-86.4	6.1	1.8	0.3	Pass	Pass	Pass
850MHz	PCL	Frequency Error	Phase Error Peak	Phase Error RMS	Power	P/T	Modulation	Switching
		<0.1ppm	<20°	<5°				
128	5	-40.6	6.6	1.6	32.8	Pass	Pass	Pass
	12	-37.4	4	1.5	19	Pass	Pass	Pass
	19	-34.3	4.4	1.5	5	Pass	Pass	Pass
189	5	-32.8	4.6	1.5	32.8	Pass	Pass	Pass
	12	-30.7	4.1	1.4	19	Pass	Pass	Pass
	19	-32.5	3.8	1.5	5	Pass	Pass	Pass
251	5	-32.4	4.6	1.4	32.7	Pass	Pass	Pass
	12	-32.7	3.7	1.4	19	Pass	Pass	Pass
	19	-26.6	4.1	1.4	5	Pass	Pass	Pass
1900MHz	PCL	Frequency Error	Phase Error Peak	Phase Error RMS	Power	P/T	Modulation	Switching
		<0.1ppm	<20°	<5°				
512	0	-70.4	8.1	1.9	29.9	Pass	Pass	Pass
	7	-69.1	5.2	1.7	16.3	Pass	Pass	Pass
	15	-65.4	5.2	1.6	0.4	Pass	Pass	Pass
661	0	-59.5	6.9	1.7	29.9	Pass	Pass	Pass
	7	-73	5.2	1.6	16.3	Pass	Pass	Pass
	15	-66.4	4.6	1.6	0.5	Pass	Pass	Pass
810	0	-75.5	7.2	1.8	29.8	Pass	Pass	Pass

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7	-58.9	5.6	1.8	16.3	Pass	Pass	Pass
15	-57.5	5.6	1.6	0.4	Pass	Pass	Pass

7.5 Table X²(p, d)

d	p													
	0.99	0.975	0.95	0.9	0.8	0.75	0.5	0.25	0.2	0.1	0.05	0.03	0.01	0.001
1	0.0002	0.00098	0.0039	0.016	0.064	0.1	0.455	1.32	1.64	2.71	3.841	5.02	6.635	10.83
2	0.0201	0.05064	0.1026	0.211	0.446	0.58	1.386	2.77	3.22	4.61	5.991	7.38	9.21	13.82
3	0.1148	0.2158	0.3518	0.584	1.005	1.21	2.366	4.11	4.64	6.25	7.815	9.35	11.34	16.27
4	0.2971	0.48442	0.7107	1.064	1.649	1.92	3.357	5.39	5.99	7.78	9.488	11.1	13.28	18.47
5	0.5543	0.83121	1.1455	1.61	2.343	2.67	4.351	6.63	7.29	9.24	11.07	12.8	15.09	20.52
6	0.8721	1.23734	1.6354	2.204	3.07	3.45	5.348	7.84	8.56	10.6	12.59	14.4	16.81	22.46
7	1.239	1.68987	2.1673	2.833	3.822	4.25	6.346	9.04	9.8	12	14.07	16	18.48	24.32
8	1.6465	2.17973	2.7326	3.49	4.594	5.07	7.344	10.2	11	13.4	15.51	17.5	20.09	26.12
9	2.0879	2.70039	3.3251	4.168	5.38	5.9	8.343	11.4	12.2	14.7	16.92	19	21.67	27.88
10	2.5582	3.24697	3.9403	4.865	6.179	6.74	9.342	12.5	13.4	16	18.31	20.5	23.21	29.59
11	3.0535	3.81575	4.5748	5.578	6.989	7.58	10.34	13.7	14.6	17.3	19.68	21.9	24.72	31.26
12	3.5706	4.40379	5.226	6.304	7.807	8.44	11.34	14.8	15.8	18.5	21.03	23.3	26.22	32.91
13	4.1069	5.00875	5.8919	7.042	8.634	9.3	12.34	16	17	19.8	22.36	24.7	27.69	34.53
14	4.6604	5.62873	6.5706	7.79	9.467	10.2	13.34	17.1	18.2	21.1	23.68	26.1	29.14	36.12
15	5.2293	6.26214	7.2609	8.547	10.31	11	14.34	18.2	19.3	22.3	25	27.5	30.58	37.7
16	5.8122	6.90766	7.9616	9.312	11.15	11.9	15.34	19.4	20.5	23.5	26.3	28.8	32	39.25
17	6.4078	7.56419	8.6718	10.09	12	12.8	16.34	20.5	21.6	24.8	27.59	30.2	33.41	40.79
18	7.0149	8.23075	9.3905	10.86	12.86	13.7	17.34	21.6	22.8	26	28.87	31.5	34.81	42.31
19	7.6327	8.90652	10.117	11.65	13.72	14.6	18.34	22.7	23.9	27.2	30.14	32.9	36.19	43.82
20	8.2604	9.59078	10.851	12.44	14.58	15.5	19.34	23.8	25	28.4	31.41	34.2	37.57	45.31
21	8.8972	10.2829	11.591	13.24	15.44	16.3	20.34	24.9	26.2	29.6	32.67	35.5	38.93	46.8
22	9.5425	10.9823	12.338	14.04	16.31	17.2	21.34	26	27.3	30.8	33.92	36.8	40.29	48.27
23	10.196	11.6886	13.091	14.85	17.19	18.1	22.34	27.1	28.4	32	35.17	38.1	41.64	49.73
24	10.856	12.4012	13.848	15.66	18.06	19	23.34	28.2	29.6	33.2	36.42	39.4	42.98	51.18
25	11.524	13.1197	14.611	16.47	18.94	19.9	24.34	29.3	30.7	34.4	37.65	40.6	44.31	52.62
26	12.198	13.8439	15.379	17.29	19.82	20.8	25.34	30.4	31.8	35.6	38.89	41.9	45.64	54.05
27	12.879	14.5734	16.151	18.11	20.7	21.7	26.34	31.5	32.9	36.7	40.11	43.2	46.96	55.48
28	13.565	15.3079	16.928	18.94	21.59	22.7	27.34	32.6	34	37.9	41.34	44.5	48.28	56.89
29	14.256	16.0471	17.708	19.77	22.48	23.6	28.34	33.7	35.1	39.1	42.56	45.7	49.59	58.3
30	14.953	16.7908	18.493	20.6	23.36	24.5	29.34	34.8	36.3	40.3	43.77	47	50.89	59.7